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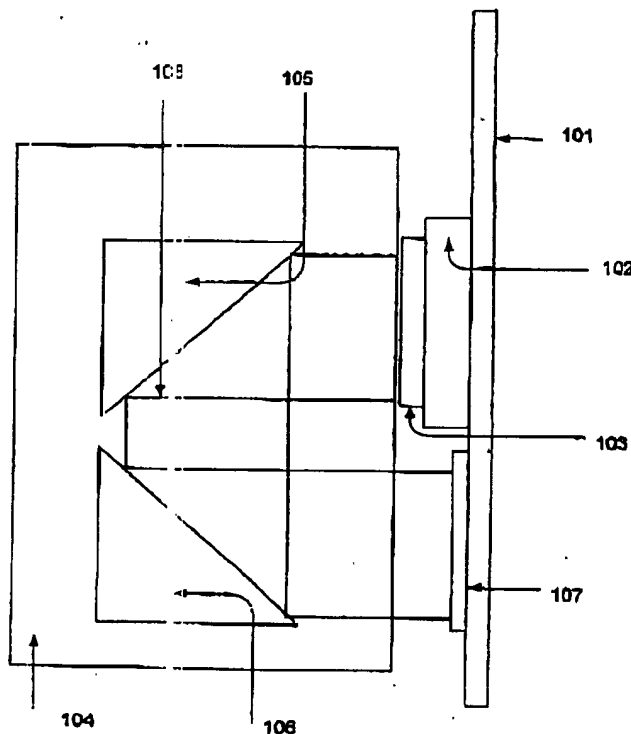
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(54) Title: **TESTING INTEGRATED CIRCUITS**



(57) Abstract: A testing apparatus for a radiation sensing integrated circuit comprises a load board (101), a test socket (102), suitable for the device under test DUT (103), and a plunger (104). A radiation source (107) is provided on the load board (101) adjacent to the test socket (102). The radiation source (107) generates radiation for testing the response to stimulus of the radiation sensing element of the DUT (103). To enable the sensing element of the DUT (103) to be exposed to the radiation, a pathway (108) is provided through plunger (104). The pathway (108) has a U-Shape with the end of one side of the U being adjacent to the radiation source (107) and the other end of the U being adjacent to the sensing element of DUT (103). Prisms (105, 106) are mounted at the base of each side of the U so as to reflect incident light along the pathway (108), such that radiation entering the pathway (108) from the radiation source (107), travels along the U and exits the other end of the U where it is then incident upon the radiation sensing element of DUT (103).

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